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(12) **United States Design Patent**
Sambu et al.

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(54) **DOOR LATCH FOR SEMICONDUCTOR MANUFACTURING EQUIPMENT**

(71) Applicant: **KOKUSAI ELECTRIC CORPORATION**, Tokyo (JP)

(72) Inventors: **Makoto Sambu**, Toyama (JP); **Satoshi Fujii**, Toyama (JP)

(73) Assignee: **KOKUSAI ELECTRIC CORPORATION**, Tokyo (JP)

(**) Term: **15 Years**

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(30) **Foreign Application Priority Data**

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(51) **LOC (13) Cl.** **08-07**

(52) **U.S. Cl.**
USPC **D8/331**

(58) **Field of Classification Search**
USPC D8/330–333, 336, 338, 343–346, D8/300–302, 306–329; 70/91, 277, 336, 70/280, 14, 51, 52, 57.1, 67, 69, 78, 85, 70/86, 88, 141; 292/340–346, 180
CPC B23K 31/02; B23K 37/00; H01R 33/76; H01R 12/58; G01R 1/073; G01R 31/26; G01R 1/0433; G01R 1/0466; G01R 31/2601; G01R 31/2867; G01R 31/2893; G01R 31/01; H01L 22/30; H01L 21/67706; H01L 21/66; H01L 21/687; E05B 69/003; E05B 71/00; E05B 73/005; E05B 17/142; E05B 47/0011; E05B 47/00; E05B 41/00; E05B 47/06; E05B 47/0001; E05B 47/0615; E05B 47/0012; E05B 15/02; E05B 65/466; E05B 65/469; E05B 13/001; E05B 13/007;
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Primary Examiner — Keli L Hill
Assistant Examiner — Sara S Sahneh
(74) *Attorney, Agent, or Firm* — Fitch, Even, Tabin & Flannery, LLP

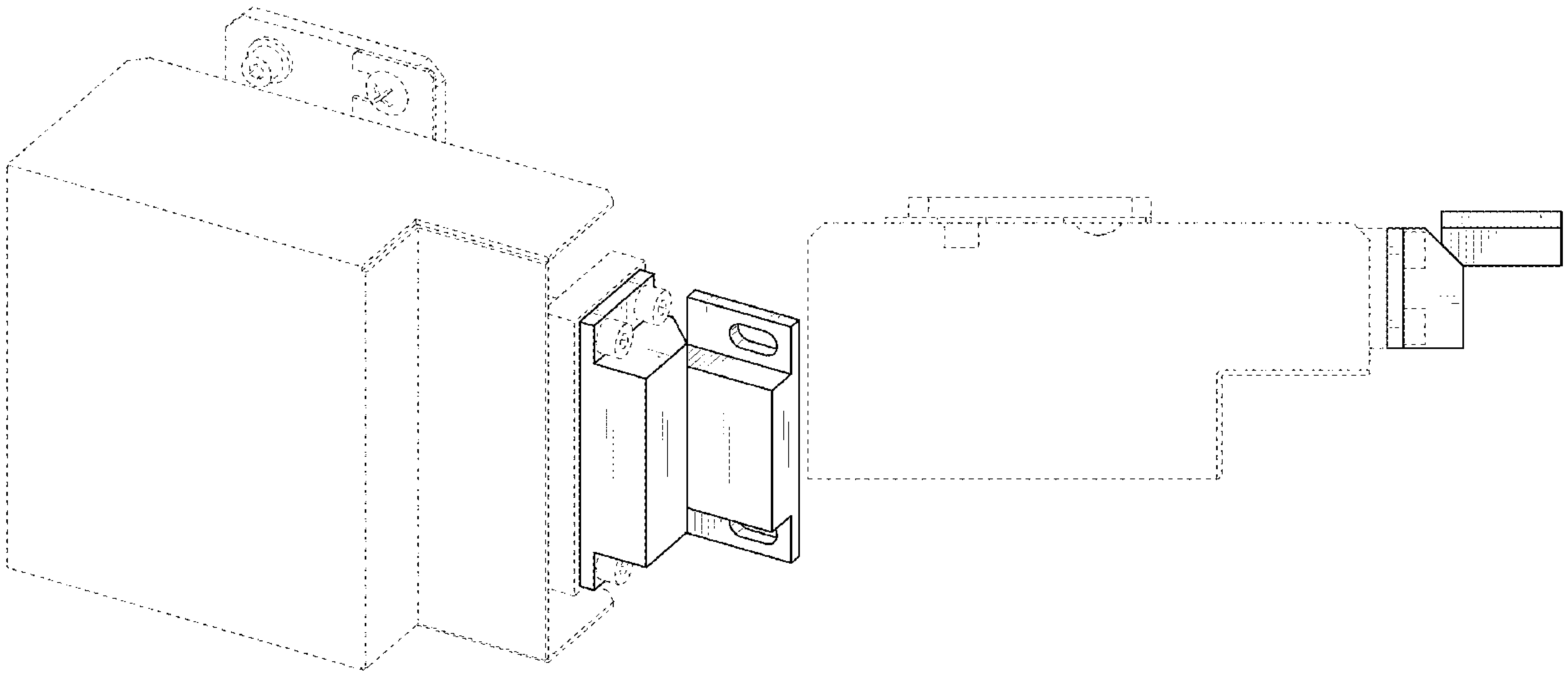
(57) **CLAIM**

We claim the ornamental design for a door latch for semiconductor manufacturing equipment, as shown and described.

DESCRIPTION

FIG. **1** is a front, top and right side perspective view of a door latch for semiconductor manufacturing equipment showing our new design;
FIG. **2** is a front elevational view thereof;
FIG. **3** is a left side elevational view thereof;
FIG. **4** is a right side elevational view thereof;
FIG. **5** is a top plan view thereof;
FIG. **6** is a bottom plan view thereof.
FIG. **7** is a rear elevational view thereof;
FIG. **8** is a cross-sectional view take along line **8**-**8** in FIG. **2** thereof; and,
FIG. **9** is a perspective illustration indicating the state that a lock was opened.
The broken lines are included for the purpose of illustrating portions of the article that form no part of the claimed design.

1 Claim, 6 Drawing Sheets



(58) **Field of Classification Search**

CPC E05B 13/00; E05B 13/10; E05B 65/44; E05B 65/46; E05B 65/462; E05B 65/463; E05B 65/461; E05B 65/464; E05B 51/00; E05B 35/00; E05B 39/00; E05B 17/14; E05B 2047/0086; B62H 5/001; Y10T 70/5155; Y10T 70/5199; A47F 3/00; A47F 3/005; A47F 3/007; A47F 7/024; G07C 9/00563

See application file for complete search history.

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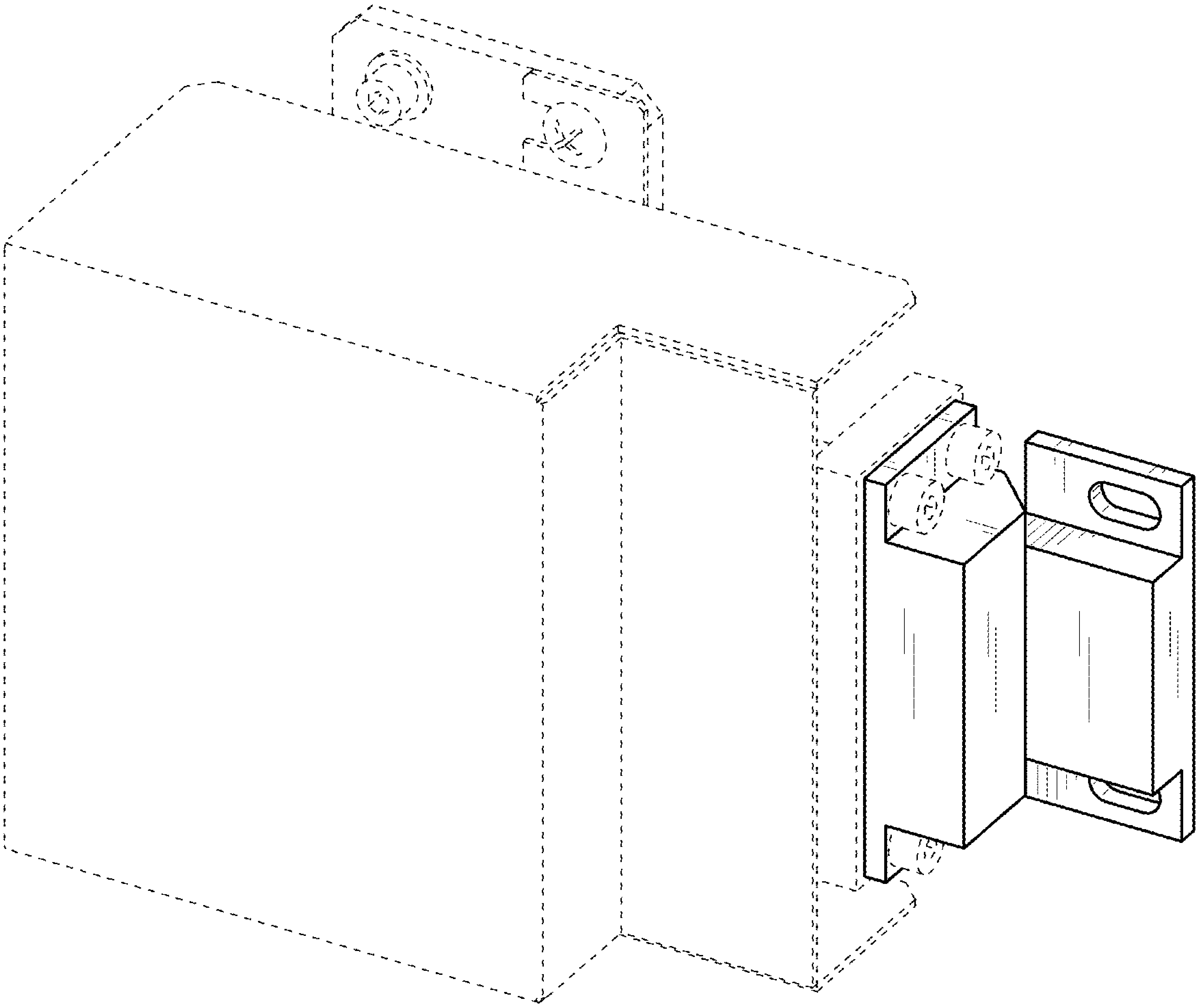

FIG. 1

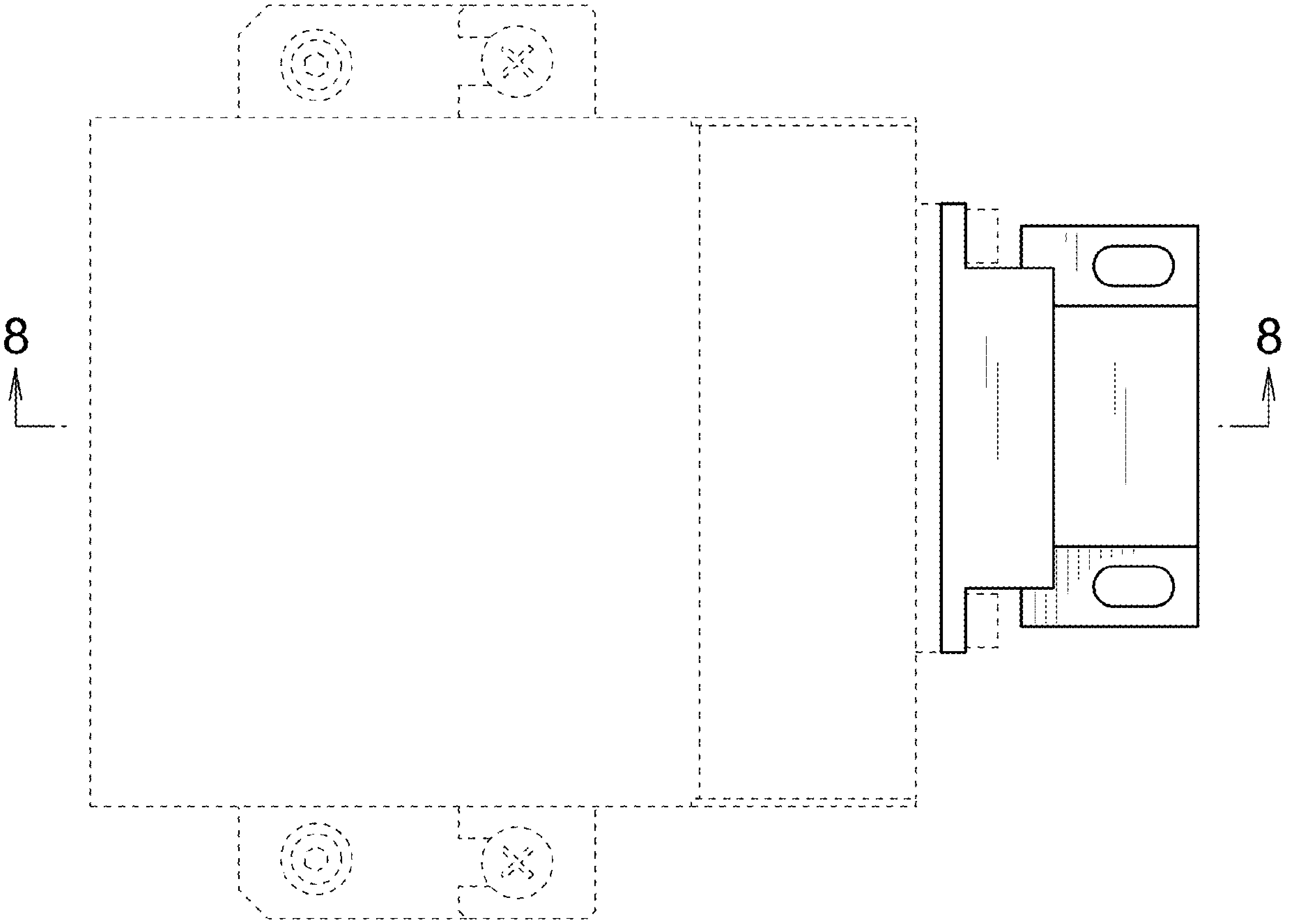

FIG. 2

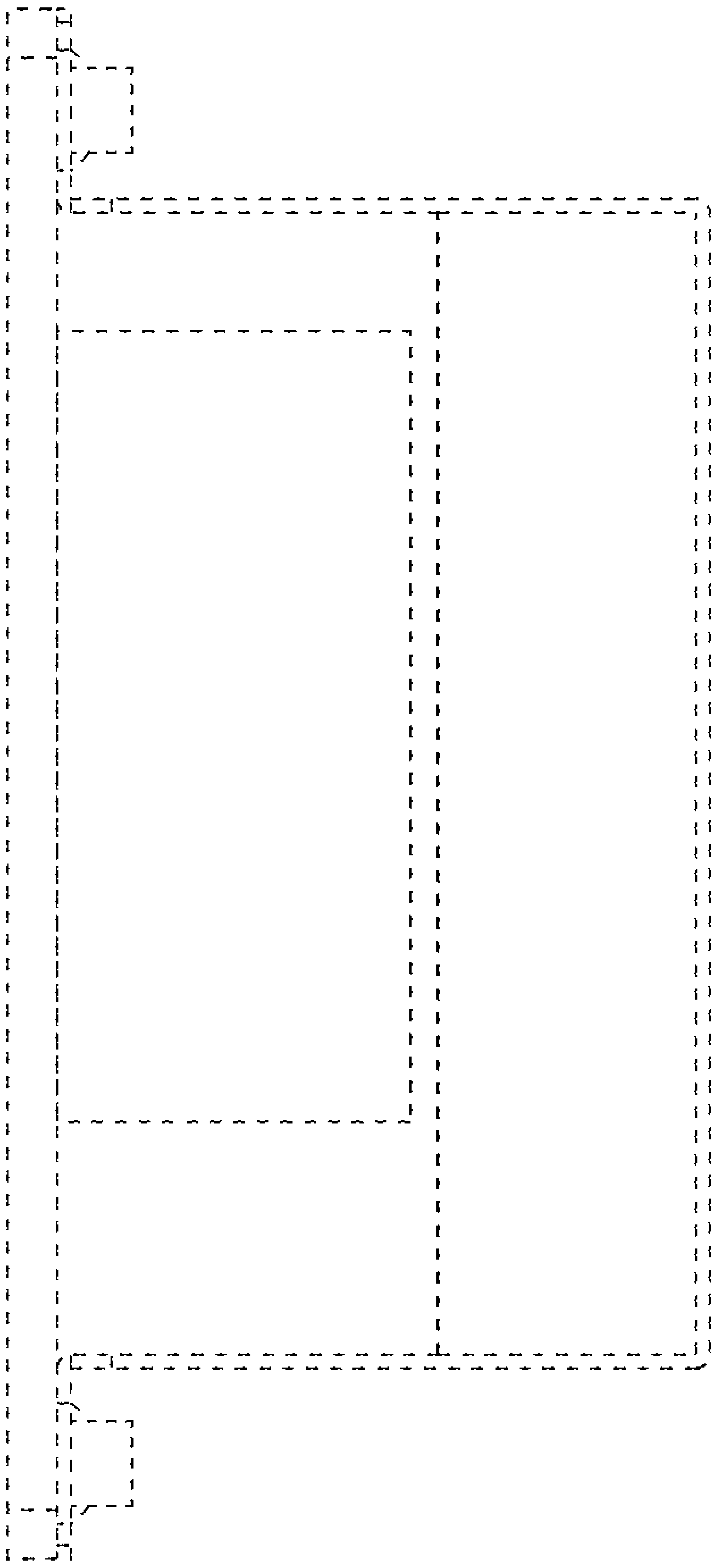

FIG. 3

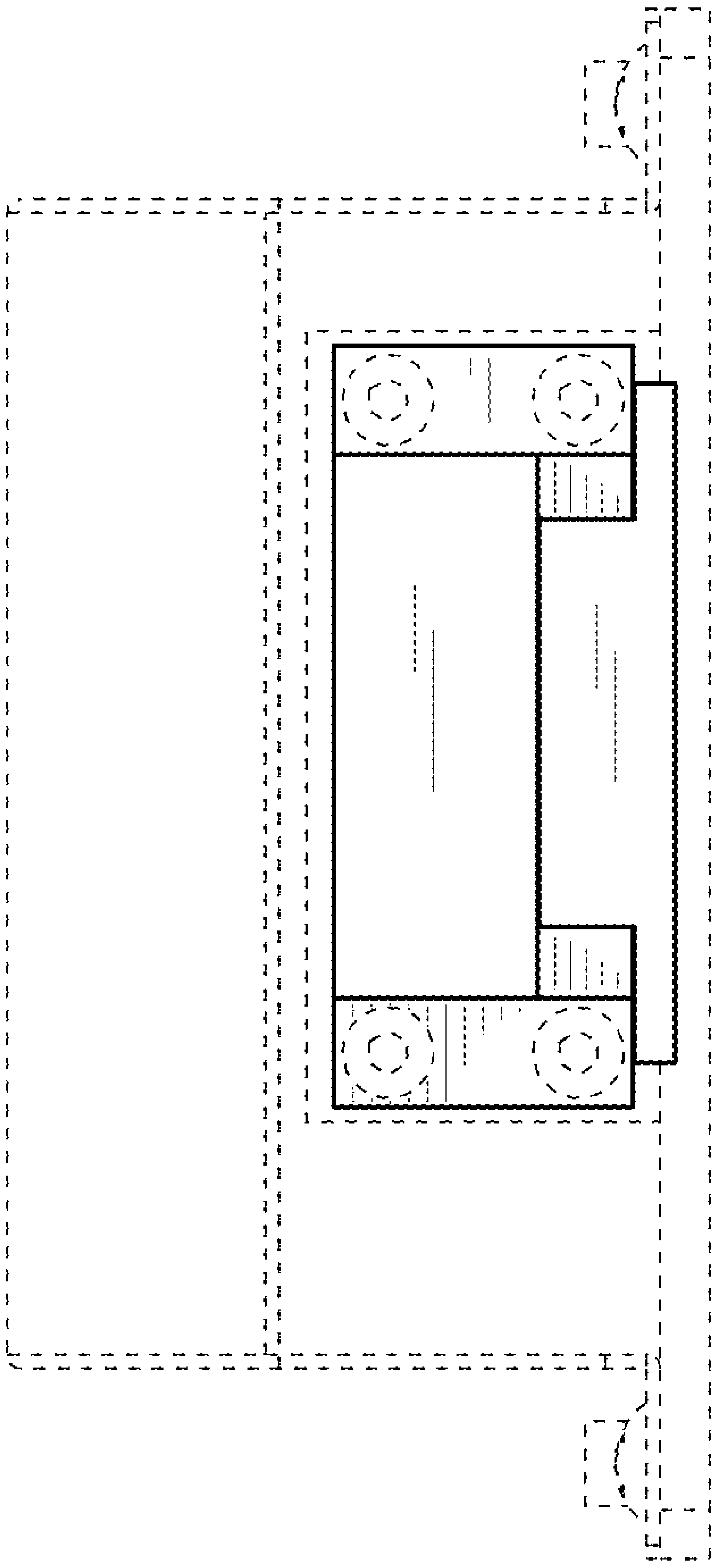

FIG. 4

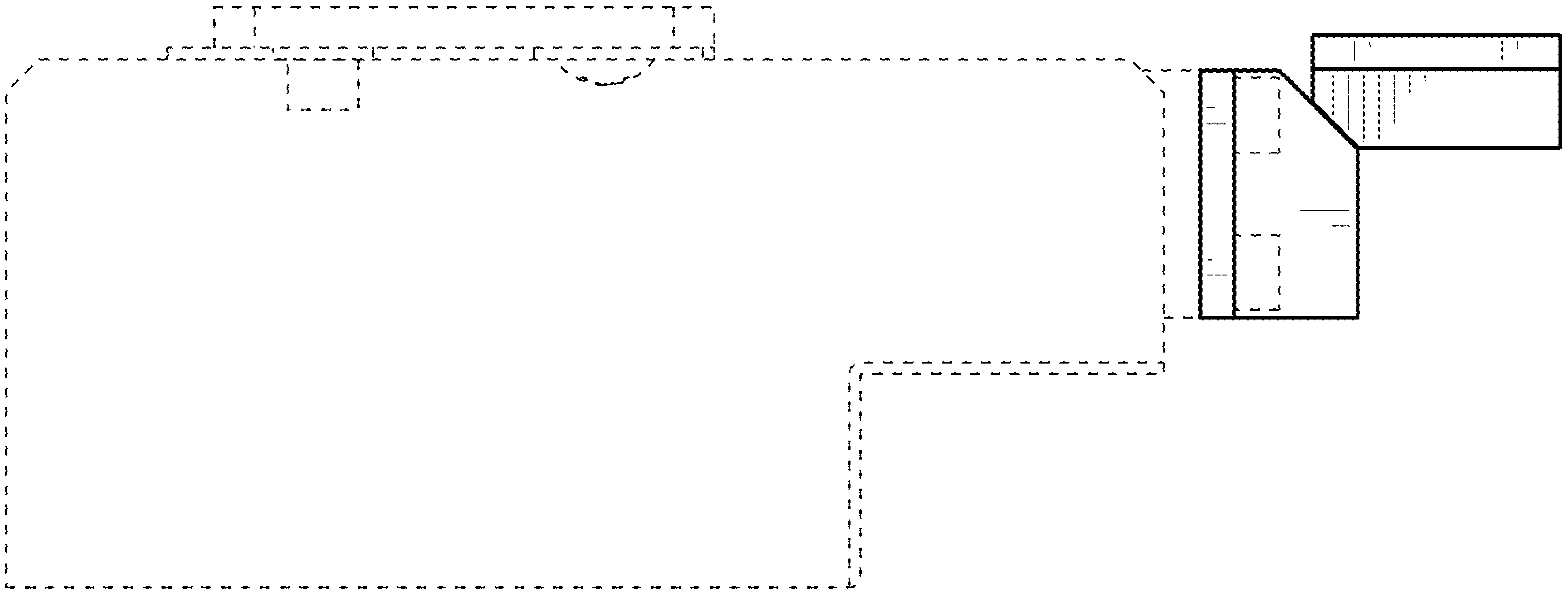

FIG. 5

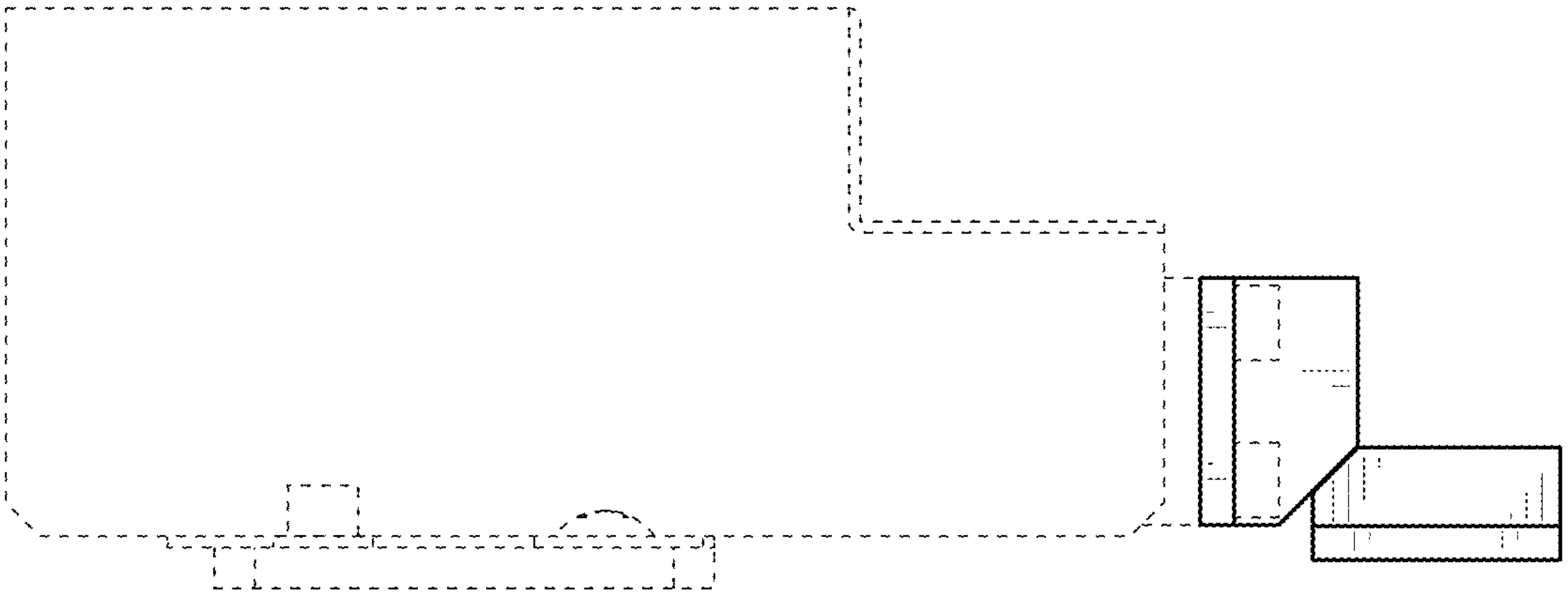

FIG. 6

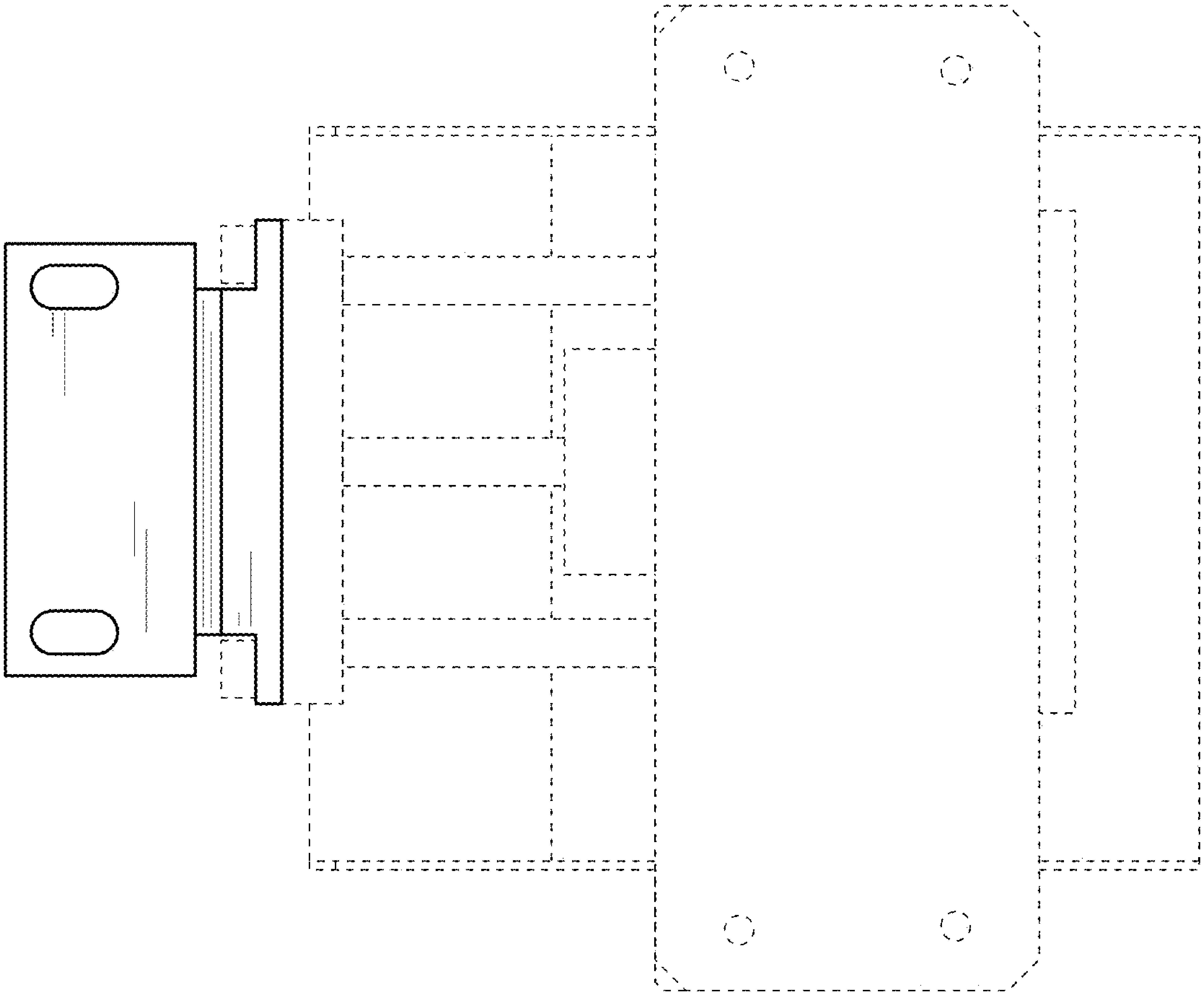

FIG. 7

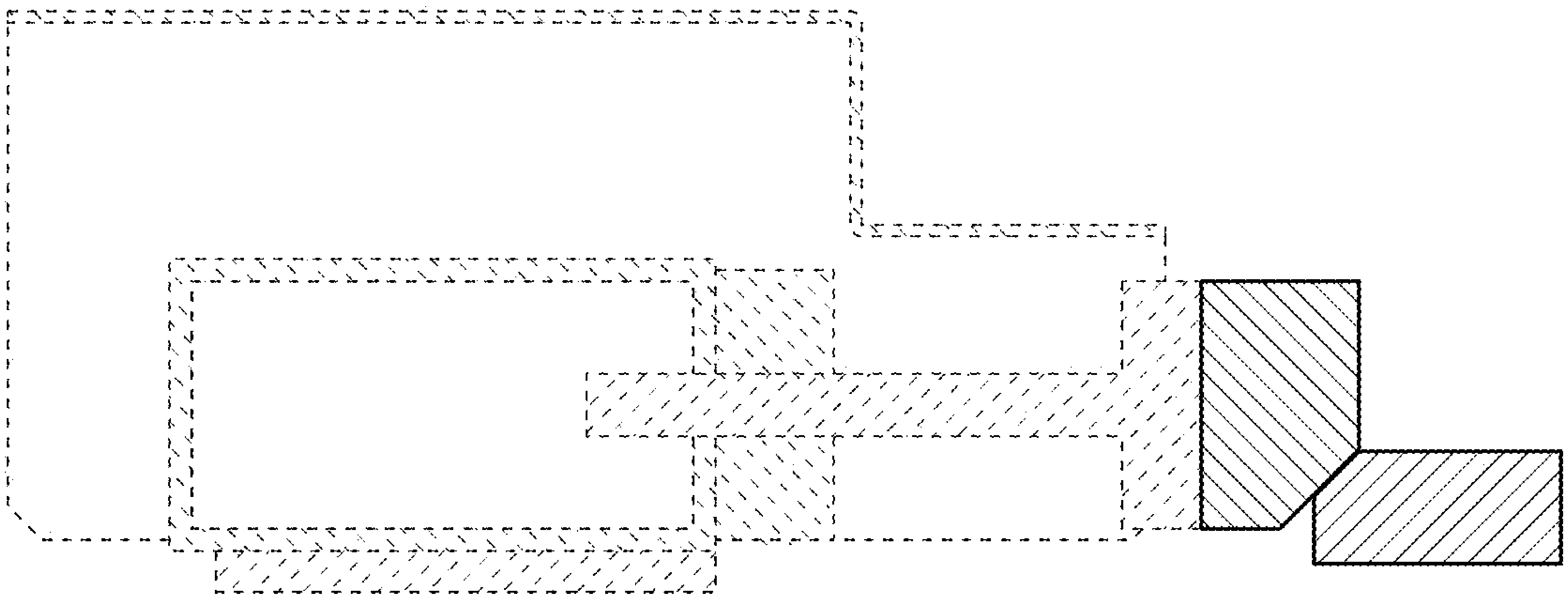

FIG. 8

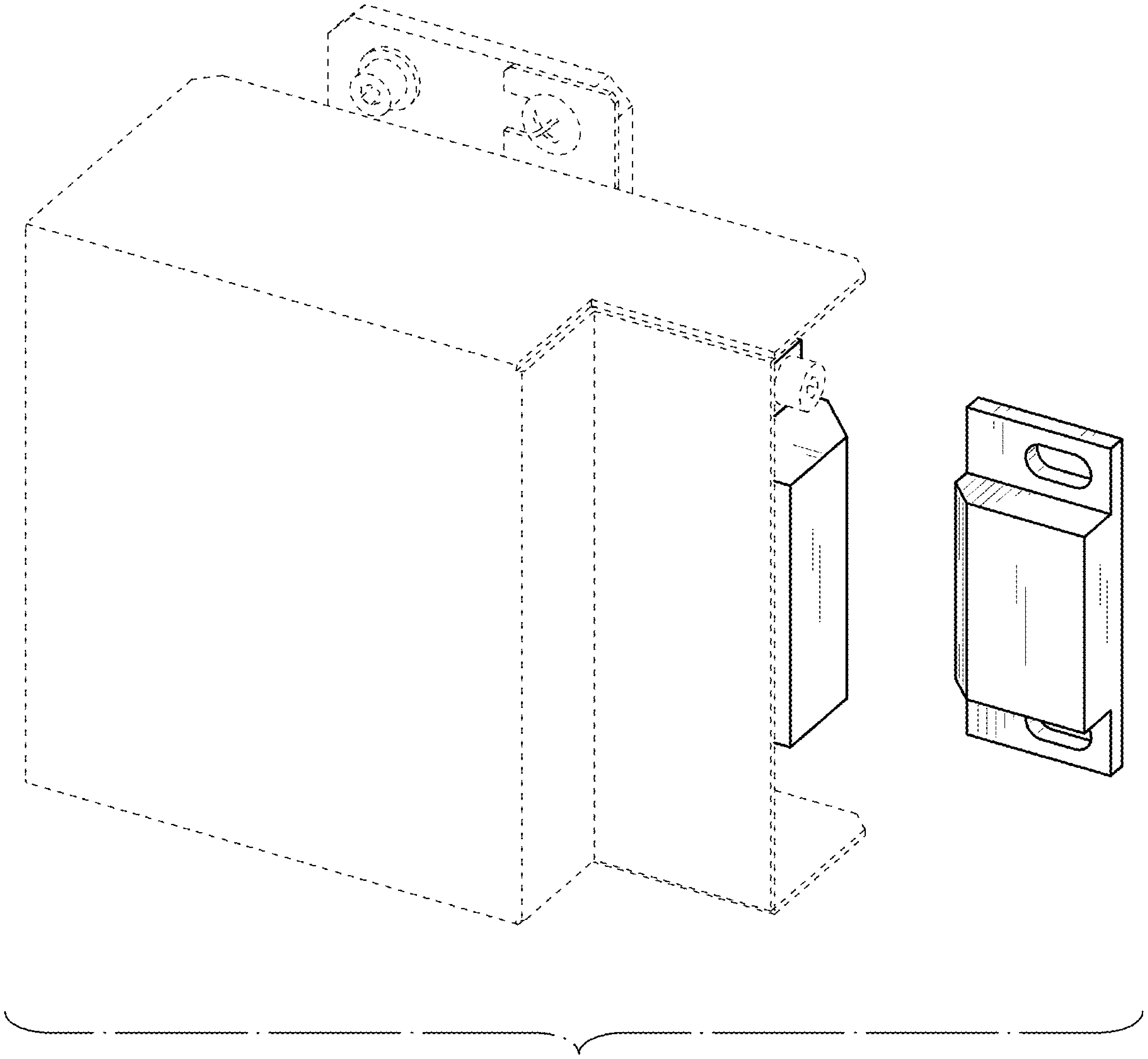

FIG. 9